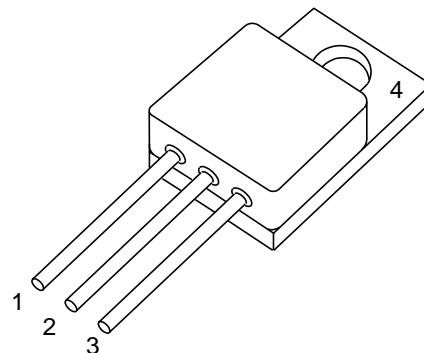


HiRel RadHard Power-MOS

- Low $R_{DS(on)}$
- Single Event Effect (SEE) hardened
LET 55, Range: 90µm
 V_{GS} : 0V to -15V, $V_{DS} = 250V$, approved
 V_{GS} : -15V to -20V, $V_{DS} = 160V$, approved
- Total Ionisation Dose (TID) hardened
100 kRad approved (Level R)
- Hermetically sealed
- N-channel



Type	Marking	Pin Configuration				Package
		1	2	3	4	
BUY25CS45B-01	-	D	S	G	Not connected	TO-254AA

Maximum Ratings

Parameter	Symbol	Values	Unit
Drain Source Voltage	V_{DS}	250	V
Gate Source Voltage	V_{GS}	+/- 20	V
Drain Gate Voltage	V_{DG}	250	V
Continuous Drain Current $T_C = 25\text{ }^{\circ}\text{C}$ $T_C = 100\text{ }^{\circ}\text{C}$	I_D	45 29	A
Continuous Source Current	I_S	45	A
Drain Current Pulsed, t_p limited by T_{jmax}	I_{DM}	180	Apk
Total Power Dissipation ¹⁾	P_{tot}	208	W
Junction Temperature	T_J	-55 to + 150	$^{\circ}\text{C}$
Operating and Storage Temperature	T_{op}	-55 to + 150	$^{\circ}\text{C}$
Avalanche Energy	E_{AS}	380	mJ

Thermal Characteristics

Thermal Resistance (Junction to Case)	$R_{th\ JC}$	0.6	K/W
Soldering Temperature	T_{sol}	250	$^{\circ}\text{C}$

Notes.:

1) For $T_S \leq 25\text{ }^{\circ}\text{C}$. For $T_S > 25\text{ }^{\circ}\text{C}$ derating is required.

Electrical Characteristics, at $T_A=25^\circ\text{C}$; unless otherwise specified

Parameter	Symbol	Values		Unit
		min.	max.	

DC Characteristics

Breakdown Voltage Drain to Source $I_D = 0.25\text{mA}$, $V_{GS} = 0\text{V}$	B_{VDSS}	250	-	V
Gate Threshold Voltage $I_D = 1.0\text{mA}$, $V_{DS} \geq V_{GS}$	$V_{GS(\text{th})}$	2.0	4.0	V
Gate to Source Leakage Current $V_{DS} = 0\text{V}$, $V_{GS} = +/- 20\text{V}$	I_{GSS}	-	+/-100	nA
Drain Current $V_{DS} = 200\text{V}$, $V_{GS} = 0\text{V}$	I_{DSS}	-	25	μA
Drain Source On Resistance ¹⁾ $V_{GS} = 10\text{V}$, $I_D = 29\text{A}$	$r_{DS(\text{ON})}$	-	0.05	Ω
Source Drain Diode, Forward Voltage ^{1), 2)} $V_{GS} = 0\text{V}$, $I_S = 45\text{A}$	V_{SD}	-	1.4	V

AC Characteristics

Turn-on Delay Time $V_{DD} = 50\% V_{DS}$, $I_D = 29\text{A}$, $R_G = 4.7\Omega$	$t_{d(\text{ON})}$	-	50	ns
Rise Time $V_{DD} = 50\% V_{DS}$, $I_D = 29\text{A}$, $R_G = 4.7\Omega$	t_r	-	95	ns
Turn-off Delay Time $V_{DD} = 50\% V_{DS}$, $I_D = 29\text{A}$, $R_G = 4.7\Omega$	$t_{d(\text{OFF})}$	-	80	ns
Fall Time $V_{DD} = 50\% V_{DS}$, $I_D = 29\text{A}$, $R_G = 4.7\Omega$	t_f	-	75	ns
Reverse Recovery Time $V_{DD} < 50\% V_{DS}$, $I_D = 45\text{A}$	t_{rr}	-	600	ns
Common Source Input Capacitance $V_{DS} = 100\text{V}$, $V_{GS} = 0\text{V}$, $f = 1.0\text{MHz}$	C_{iss}	3.5	6.5	nF
Common Source Output Capacitance $V_{DS} = 100\text{V}$, $V_{GS} = 0\text{V}$, $f = 1.0\text{MHz}$	C_{oss}	250	400	pF
Common Source Reverse Transfer Capacitance $V_{DS} = 100\text{V}$, $V_{GS} = 0\text{V}$, $f = 1.0\text{MHz}$	C_{rss}	5	20	pF
Total Gate Charge $V_{DD} = 50\% V_{DS}$, $V_{GS} = 10\text{V}$, $I_D = 45\text{A}$	Q_G	-	100	nC

Notes.:

- 1) Pulsed Measurement: Pulse Width < 300 μs , Duty Cycle < 2.0%.
2) Measured within 2.0 mm of case.

Electrical Characteristics

at $T_A=125^\circ\text{C}$; unless otherwise specified

Parameter	Symbol	Values		Unit
		min.	max.	

DC Characteristics

Gate Threshold Voltage $I_D = 1.0\text{mA}$, $V_{DS} \geq V_{GS}$	$V_{GS(\text{th})}$	1.5	-	V
Gate to Source Leakage Current $V_{DS} = 0\text{V}$, $V_{GS} = +/- 20\text{V}$	I_{GSS}	-	+/-200	nA
Drain Current $V_{DS} = 200\text{V}$, $V_{GS} = 0\text{V}$	I_{DSS}	-	250	μA
Drain Source On Resistance ¹⁾ $V_{GS} = 10\text{V}$, $I_D = 29\text{A}$	$r_{DS(\text{ON})}$	-	0.09	Ω

Notes.:

1) Pulsed Measurement: Pulse Width < 300 μs , Duty Cycle <2.0%.

Electrical Characteristics

at $T_A=-55^\circ\text{C}$; unless otherwise specified

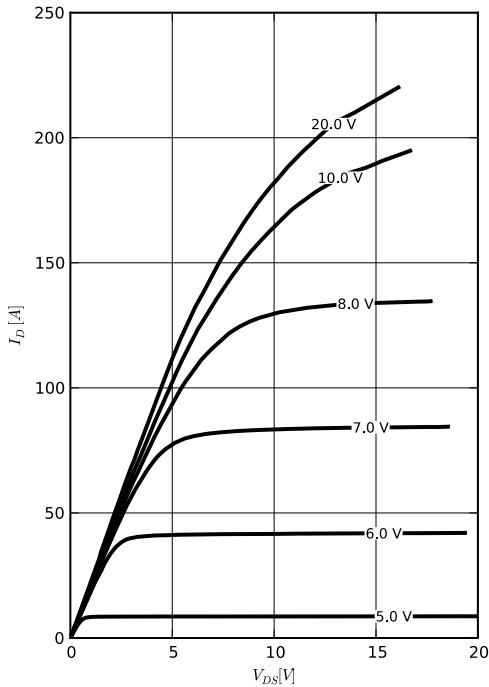
Parameter	Symbol	Values		Unit
		min.	max.	

DC Characteristics

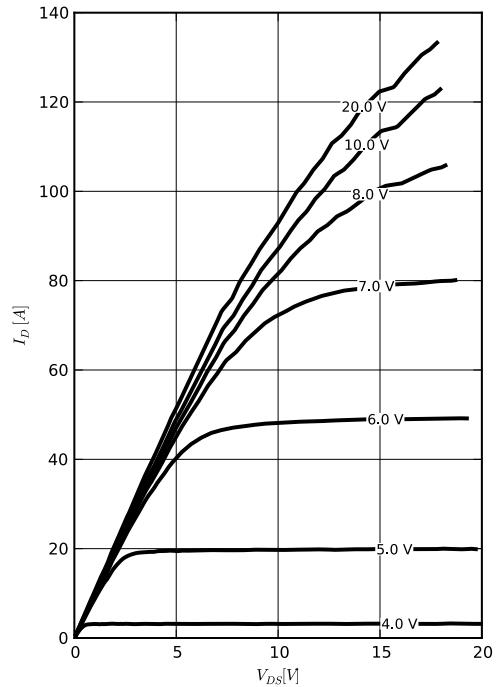
Gate Threshold Voltage $I_D = 1.0\text{mA}$, $V_{DS} \geq V_{GS}$	$V_{GS(\text{th})}$	-	5.0	V
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1 Typ. output characteristics

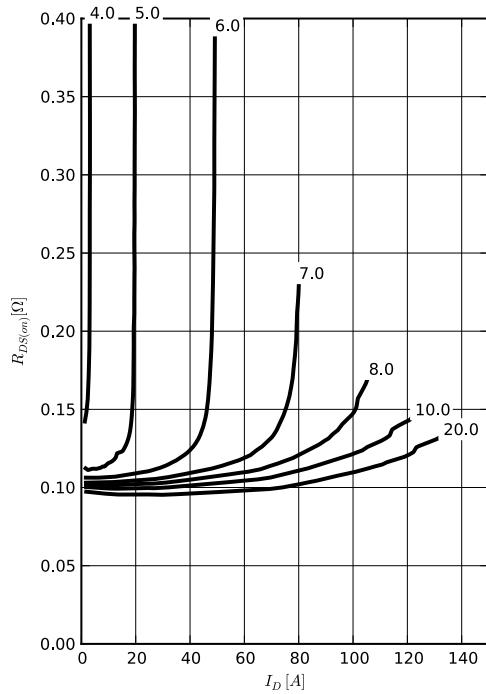
$I_D = f(V_{DS})$; $T_j = 25^\circ C$
parameter: V_{GS}


2 Typ. output characteristics

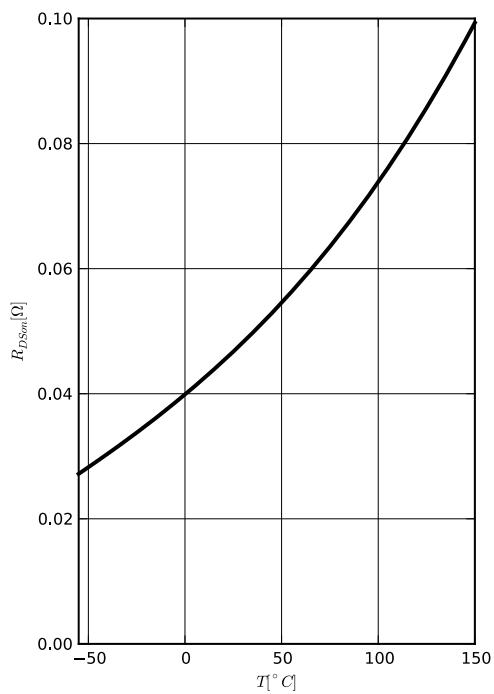
$I_D = f(V_{DS})$; $T_j = 150^\circ C$
parameter: V_G


3 Typ. drain-source on-state resistance

$R_{DS(on)} = f(I_D)$; $T_j = 150^\circ C$
parameter: V_{GS}

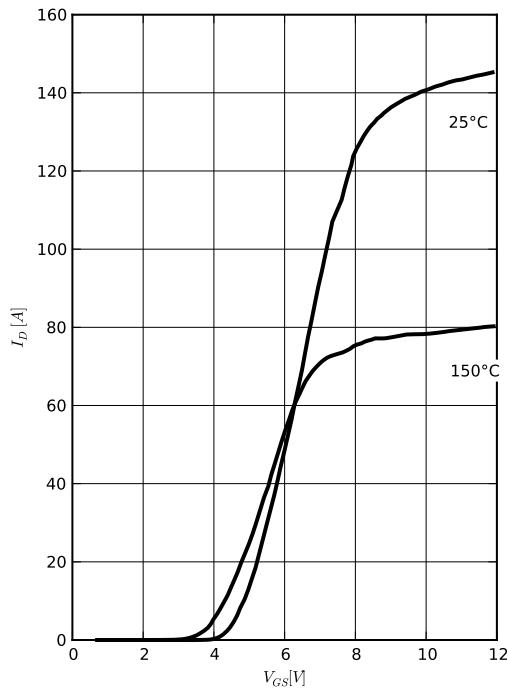

4 Typ. drain-source on-state resistance

$R_{DS(on)} = f(T_j)$
 $I_D = 29 A$

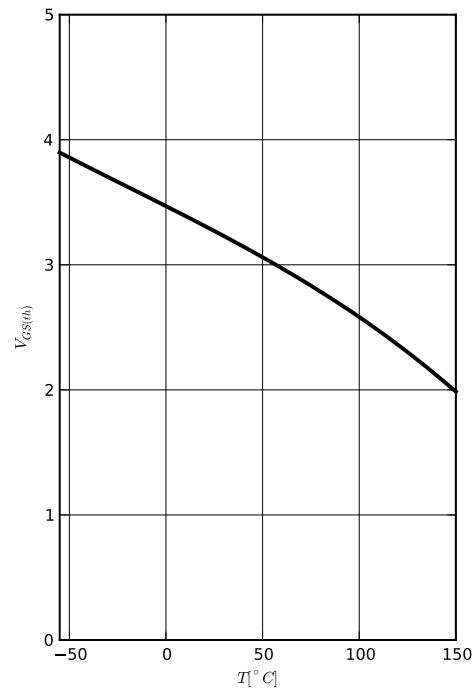


5 Typ. transfer characteristics

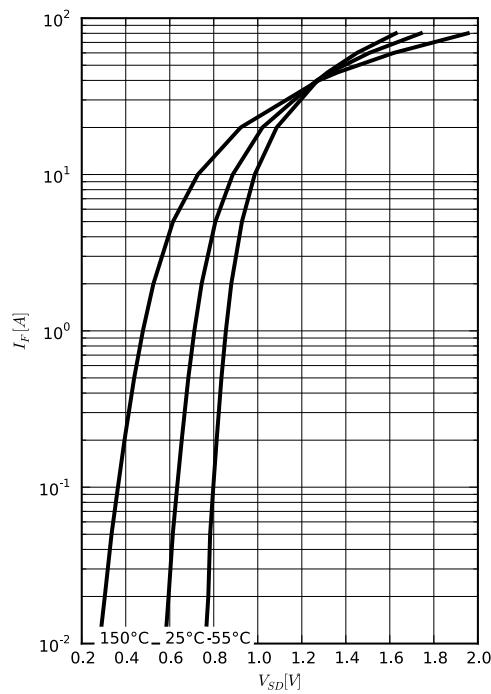
$I_D = f(V_{GS})$; $|V_{DS}| > 2 |I_D| R_{DS(on)max}$
 parameter: T_j


6 Typ. gate threshold voltage

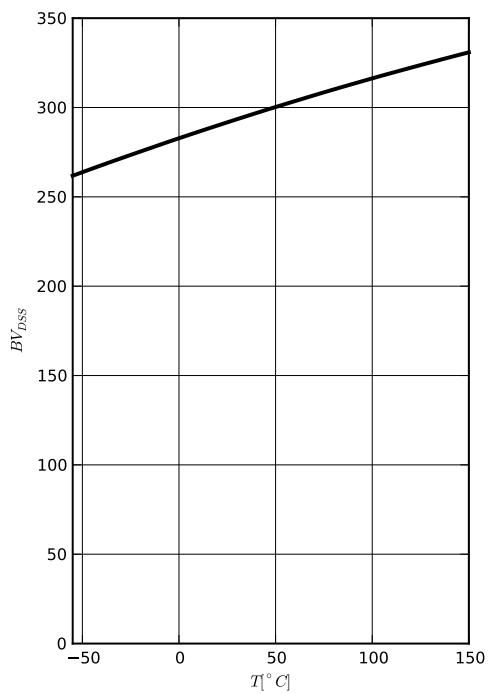
$I_D=f(T_j)$
 $I_D = 1mA$


7 Typ. forward characteristics of reverse diode

$I_F = f(V_{SD})$
 parameter: T_j

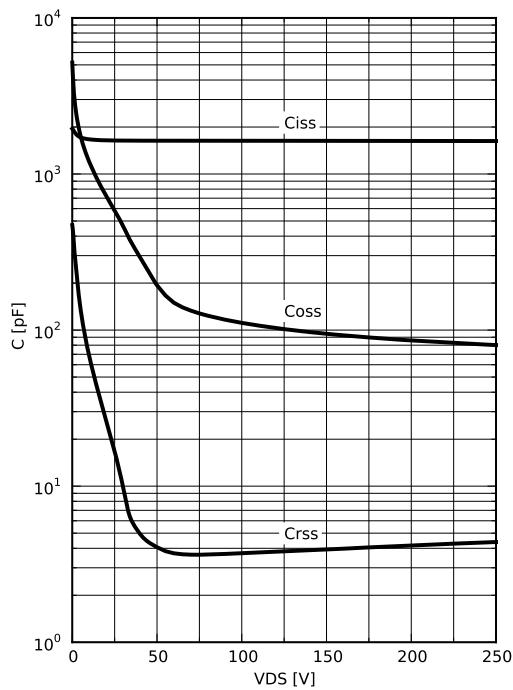

8 Typ. drain-source breakdown voltage

$BV_{DSS}=f(T_j)$
 $I_D = 250\mu A$

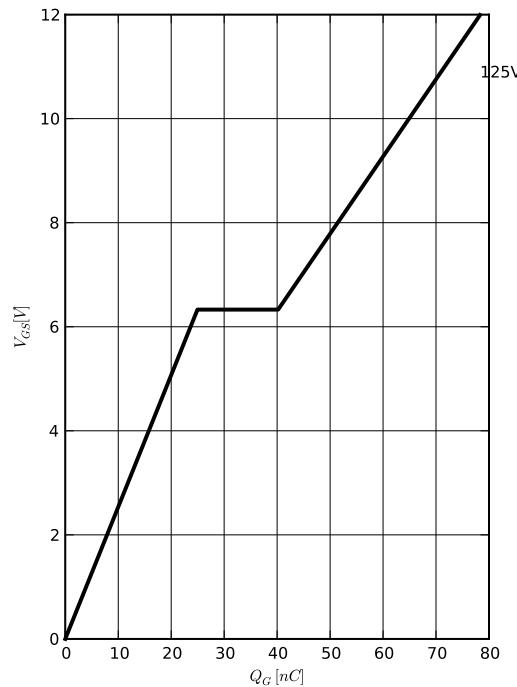


9 Typ. capacitances

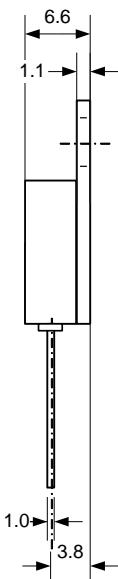
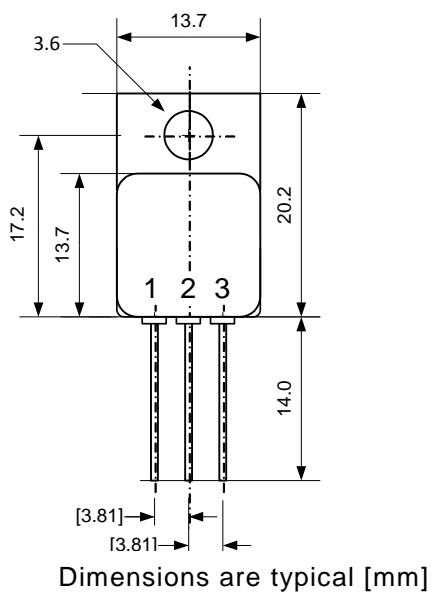
$C = f(V_{DS})$; $V_{GS} = 0$ V; $f = 1$ MHz


10 Typ. gate charge

$V_{GS} = f(Q_{gate})$; $ID = 45.0$ A pulsed parameter: V_{DD}



TO-254AA Package



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